

Sonix HS500 HiSPEED Acoustic Microscope System

DESCRIPTION:

- Non-destructive test uses ultra-sound to characterize samples
- Used to find voids, cracks, delamination, die tilt, etc.
- Scan at a specified depth to collect data at desired interfaces
- Pulse echo and through scan capabilities
- Create 3-D images, vertical cross section images
- 10, 15, 50, 110 and 150 MHz transducers available

LOCATION: IEEC RELIABILITY LAB

[CONTACT US](#)



CONTACTS

For more information or to arrange for the use of this equipment, contact any of the IEEC staff members listed below:

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